รายการอ้างอิง

1. บริษัท ไลอ้อน คอนเทนเนอร์ส จำกัด. Internal Communication. 2004

2. Chin, R. T. and Charles, A. H.. Automate Visual Inspection : A Survey. IEEE Transactions on Pattern Analysis and Machine Intelligence. 4,6 (November 1992) : 557-573

3. Matsushita Electric Works Co. Ltd.. Vision System – Image Checker 30 Manual. Osaka, Japan, 1990

4. Edward R. Dougherty. Digital Image Processing Methods. New York : Dekker, 1994

5. Gonzalez, R.C. and Woods, R.E.. Digital Image Processing. New York : Addison-Wesley Publishing, 1992

6. Gregory A Baxes. Digital Image Processing : Principle and Applications. John Wiley & Sons, 1994

7. Manachai Udondee. Image Processing Application in Aluminum Alloy Wheel Inspection. Degree of Master of Engineering Department of Electrical Engineering Chulalongkorn University, 2541

8. Haralick, R. M. and Shapiro. L.G. Computer and Robot Vision volume 1-2. New York : Addison-Wesley Publishing, 1992

9. Jain A. K.. Fundamental of Digital Image Processing. New Jersey : Pretice-Hall International., 1989

10. Fu K. S.. Pattern Recognition for Automatic Visual Inspection. IEEE Computer (December 1992): 34 - 40

11. Mihini, B.. Fast Visual Inspection for Quality Control. Ph.d. dissertation The University of Nottingham, UK, 1989

12. Hiroi, T., Maeda, S., Kubota, H. Watanabe, K. and Nakagawa, Y. Precise Visual Inspection for LSI Wafer Pattern using Subpixel Image Alignment. Proceedings of the second IEEE workshop on Application of Computer Vision. 1994. pp.26-34, Sorasato, USA, December 5-7, 1990. : IEEE Comput.Soc. Press 1994

13. Teoh, E. K., Mital, D. P., Lee, B. W. and Wee, L. W.. Automated Visual Inspection of Surface Mount PCBs. IECON'90 16th Annual Conference of IEEE Industrial Electronics Society. pp.576 – 580, Pacific Grove, CA, USA, November 27 – 30, 1990 : IEEE New York, 1990

14. Perner, P.. An Architecture for a Knowledge-Base Image Inspection System. ISSIPNN'94 1994 International Symposium on Speech, Image Processing and Neural Network Processing, pp.65 – 68, Hong Kong, April 13 –16, 1994. : IEEE New York, USA, 1994

15. Chryler Corporation, Ford Motor Company, and General Motors Corporation. Statistical Process Control (SPC). 1992

16. Truchelet, F., Cholley, J. P., Hemming, S.. Tampoprint Inspection by Artificial Vision. IECon'93 International Conference on Industrial Electronics Control and Instrumentation, pp.1882-1887, Maul, Hi, USA, November 15-19, 1993. : IEEE New York, USA, 1993.Chin,Y.H. Computer Vision for Industrial Inspection through Linguistic Fuzzy Variable. 20th International Conference on Industrial Electronics, Control and Instrumentation , pp 1349-1353. 2, Bologna, Italy, Sept 5-9 1994 : IEEE New York, USA, 1994

17. Sato K., Kan'no H., and Ito H.. System for Inspecting pad-printed characters using the normalized correlation of the segmented character images. IECON'91 1991 International Conference on Industrial Electronics, Control and Instrumentation. 1929-1932. 3, Kobe, Japan, 28 October – 1 November, 1991 : IEEE New York USA, 1991

18. Safabakhsh, R.. Computer Vision Techniques for Industrial Applications and Robot Control. IEEE Computer. (December 1992) : 17-32

19. Jain, R., Kasturi, R. and Schunck, B.G.. Machine Vision. Singapore : McGraw-Hill, 1995

20. Kreyszig, E.. Advance Engineering Mathematics. New York : John Wiley & Sons, 1998

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นายปรีติ ประชาฤทธิ์ภักดี เกิดเมื่อวันที่ 30 กรกฎาคม พ.ศ. 2524 ที่จังหวัดสมุทรสงคราม สำเร็จการศึกษาขั้นปริญญาวิศวกรรมศาสตรบัณฑิต   สาขาวิชาวิศวกรรมไฟฟ้า   จากคณะ วิศวกรรมศาสตร์ จุฬาลงกรณ์มหาวิทยาลัย เมื่อปี พ.ศ. 2544